

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BHATNAGAR ET AL.	
		Examiner Benjamin E. Lanier	Art Unit 2132	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0027440	10-2001	Tanaka et al.	705/39
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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